

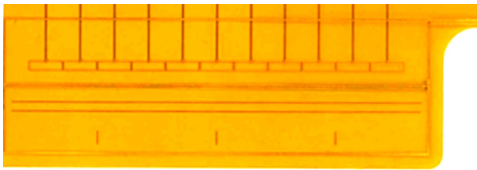
jET™

The JENTEK® Eddy Current Array (ECA) Tester

With conformable **MWM®-Array** technology

- **BEST** detection and characterization performance
- **VERY LOW** false indication rates
- **REDUCED** surface preparation
- **NOW** in a small, convenient and lightweight package that **fits your budget!**

With Proven MWM-Array Performance



Deep Penetration MWM-Array



- **Engine Component Inspection**
 - Blades, disks, IBRs, holes, etc.
- **NDT of Complex Structures** (per ASTM E2884-13 Standard Guide for Eddy Current Testing of Electrically Conducting Materials Using Conformable Sensor Arrays, ASTM International, Book of Standards, Vol. 03.03.)
 - Surface breaking and subsurface cracks
 - Hidden corrosion
- **Coating Characterization** without need of expensive custom calibration standards (per ASTM E2338-11 Standard Practice for Characterization of Coatings Using Conformable Eddy-Current Sensors without Coating Reference Standards, ASTM International, Book of Standards, Vol. 03.03.)
- **Complex Shaped Surfaces**
 - Firtree slots in engine disks, fillets in aircraft structures, etc.
- **Materials/Process Quality Characterization**

JENTEK® Sensors, Inc.

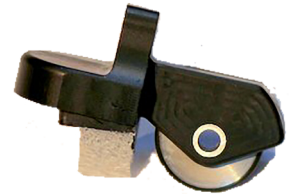
- **JENTEK Founded in 1992**
- **JENTEK Core Competencies**
Model-Based Inverse Methods,
Electronics Design, NDT/NDE/NDI, SHM
- **JENTEK focus is improving safety and quality while delivering high ROI**
- **MWM-Array**
 - Winner FAA/ATA “Better Way” Award
 - National Tibbets Award
 - ASNT Best Paper Award
 - U.S. Navy Phase III Commercialization Award
 - FAA approved for some engine inspections
 - U.S. Navy Standard practice for engine inspection
 - Implemented on Space Shuttle Leading Edge at NASA KSC
 - Proven to provide improved inspection performance using model based multivariate inverse methods (MIMs)
- **GridStation® Software and HyperLattice® based MIMs**
 - Intuitive operator interfaces
 - Inherent self-diagnostics
 - C-Scan imaging of multiple properties simultaneously (e.g. first and second layer corrosion, or coating conductivity and thickness)
 - Convenient procedure and data management



Periodic MWM



Near Surface MWM-Array



Hardware Specifications

Instrument Power	11.5-18V DC External PoE power adapter provided (runs off of 100-240V, 50-60 Hz AC)
Number of Channels	7 fully parallel channels
Operating Frequency	2.5Hz-21MHz (Inductive) Up to three frequencies recorded simultaneously
Overall Dimensions	2 in. Diameter x 7.5 in. Length
Weight	<1 lb. (Power over Ethernet configuration)
Encoders	2
Triggers	2 Internal and 2 External
Ethernet	100/10 MB/s (Support for PoE)
1.8 in. Diagonal display with resistive touch panel	
Haptic and audible feedback	
Requires GridStation and Windows OS Software with a suitable computer or tablet	

JENTEK GridStation advanced eddy-current inspection systems have been called “the gold standard” of inspections at U.S. Navy Depots.

JENTEK® Sensors, Inc.

GridStation, MWM, HyperLattice and JENTEK are registered trademarks of JENTEK Sensors, Inc.

JENTEK Issued patents include U.S. Patent #s: 8,981,018, 8,960,012, 8,928,316, 8,803,515, 8,768,657, 8,494,810, 8,237,433, 8,222,897, 8,050,883, 7,994,781, 7,876,094, 7,812,601, 7,696,748, 7,589,526, 5,533,575, 7,528,598, 7,526,964, 7,518,360, 7,467,057, 7,451,657, 7,451,639, 7,411,390, 7,385,392, 7,348,771, 7,289,913, 7,280,940, 7,230,421, 7,188,532, 7,183,764, 7,161,351, 7,161,350, 7,106,055, 7,095,224, 7,049,811, 6,995,557, 6,992,482, 6,952,095, 6,798,198, 6,784,662, 6,781,387, 6,727,691, 6,657,429, 6,486,673, 6,433,542, 6,420,867, 6,380,747, 6,377,039, 6,351,120, 6,198,279, 6,188,218, 6,144,206, 5,966,011, 5,793,206, 5,629,621, 5,990,677 and RE39,206 (other patents pending).

Windows is a registered trademark of Microsoft Corporation in the United States and other countries.

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